

TEXAS INSTRUMENTS  
FIELD PROGRAMMABLE LOGIC DEPARTMENT  
PROGRAMMING ALGORITHM SPECIFICATION

DEVICE FAMILY TIBPAL20XX-5  
DEVICES INCLUDED TIBPAL20R4-5, TIBPAL20R6-5, TIBPAL20R8-5, TIBPAL20L8-5.

**PROGRAMMING PROCEDURE:**

Array fuses are programmed by executing the following programming sequence. Each fuse can be opened by selecting the appropriate (1 of 32) Input Line and (1 of 8) Product Line. The levels for selecting Input Lines and Product Lines are shown in Tables 1-2 and 1-3.

- Step 1: Raise PGM ENABLE to  $V_{IHH}$ .
- Step 2: Select an Input Line by applying appropriate levels to PI pins.
- Step 3: Select a Product Line group by applying appropriate logic levels to PA pins. The actual product line selected will be determined by the PO pin (described in step 5).
- Step 4: Raise /OE to  $V_{IH}$ .
- Step 5: Raise the selected PO pin to  $V_{IHH}$ .
- Step 6: Program the fuse by pulsing VCC to  $V_{IHH}$ .
- Step 7: Remove the output voltage.
- Step 8: Lower /OE to  $V_{IL}$  to enable device.
- Step 9: Pulse PGM VER pin to  $V_{IH}$ .
- Step 10: Verify the blowing of fuse by checking for a  $V_{OL}$  at the selected PO pin.

If the fuse is still intact, steps 1 thru 10 may be repeated until the fuse is successfully blown, not to exceed 4 retries. Do not apply additional pulses to a fuse once it is correctly programmed. Verification is possible only with the Security fuse intact.

Security fuses are provided on each device to discourage the unauthorized copying of fuse patterns. To program the security fuse, follow the steps above omitting steps 2 and 10.

See Tables 1-2 and 1-3 for addressing information.

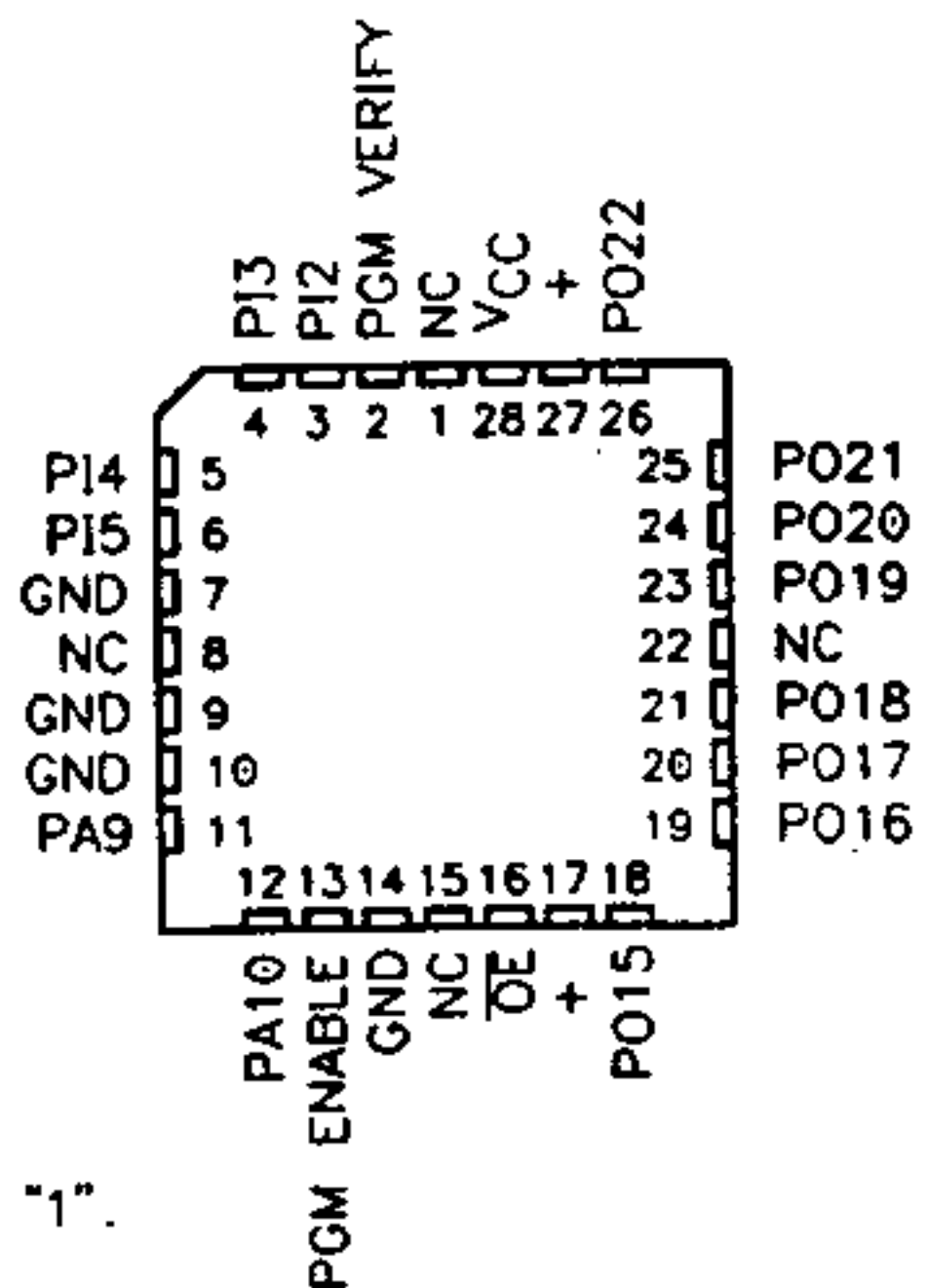
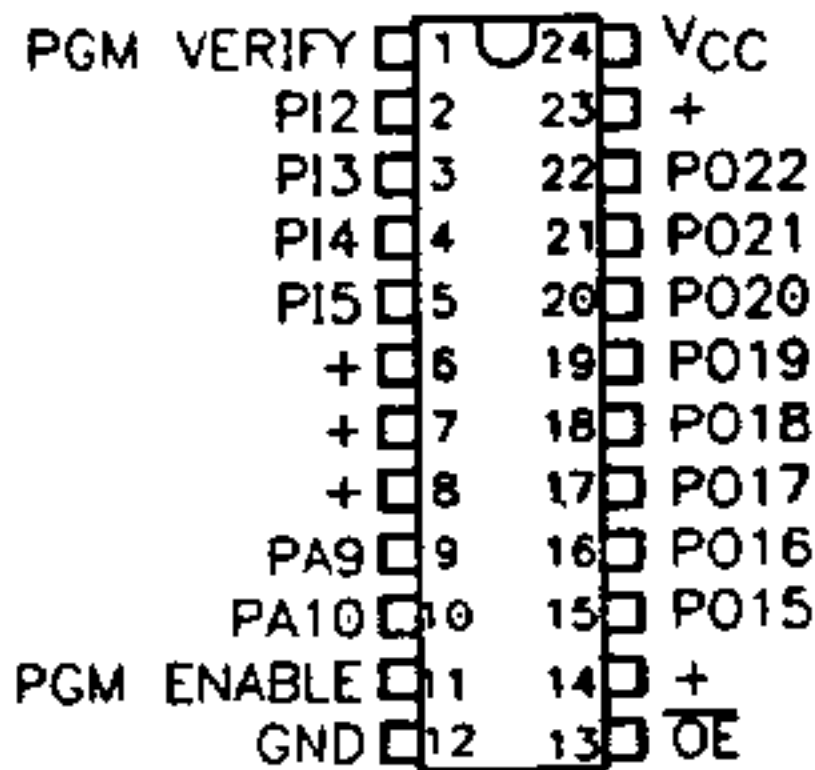
For programming waveforms, see Figure 1-1.

PREPARED BY B. Cole PAL24D-1.DWG	DATE 03/24/90	<b>TEXAS INSTRUMENTS</b>			
CHECKED BY <i>[Signature]</i>	DATE 7/17/90	<b>TITLE</b> ALGORITHM SPECIFICATION TIBPAL20XX-5			
ENGINEER <i>[Signature]</i>	DATE 7/18/90				
APPROVED BY <i>[Signature]</i>	DATE 7/18/90	REVISION B	<b>A</b> SIZE	PAL24012	SHEET 1 10
RELEASED BY <i>[Signature]</i>	DATE 1/1	LETTER	SIZE		

# PIN ASSIGNMENTS IN PROGRAMMING MODE

JT or NT PACKAGE  
(TOP VIEW)

FN or FK PACKAGE  
(TOP VIEW)



+ = Set to logical "1".

TABLE 1-1. PROGRAMMING PARAMETERS, TA = 25°C

PARAM	DESCRIPTION	MIN	NOM	MAX	UNIT
VCC	Verify-level supply voltage	4.75	5.00	5.25	V
V <sub>IH</sub>	High-level input voltage	2.40		5.50	V
V <sub>L</sub>	Low-level input voltage			0.50	V
V <sub>IHH</sub>	Program-pulse voltage	10.25	10.50	10.75	V
	PO	10.25	10.50	10.75	V
	PGM ENA	10.25	10.50	10.75	V
	PI, PA	10.25	10.50	10.75	V
	VCC	10.25	10.50	10.75	V
I <sub>IHH</sub>	Program-pulse current		20	40	ma
	PO		5	15	ma
	PGM ENA		2	10	ma
	PI, PA			450	ma
	I <sub>CC</sub>			50	ma
t <sub>w1</sub>	Program-pulse duration at PO	10			us
t <sub>w2</sub>	Pulse duration at PGM VERIFY	100			ns
t <sub>su</sub>	Set-up time	100			ns
t <sub>h</sub>	Hold time	100			ns
t <sub>d1</sub>	Delay time from /OE low to PGM VERIFY high.	100			ns
t <sub>d2</sub>	Delay time from PGM VERIFY high to valid output.	100			ns

TABLE 1-2, INPUT LINE SELECT

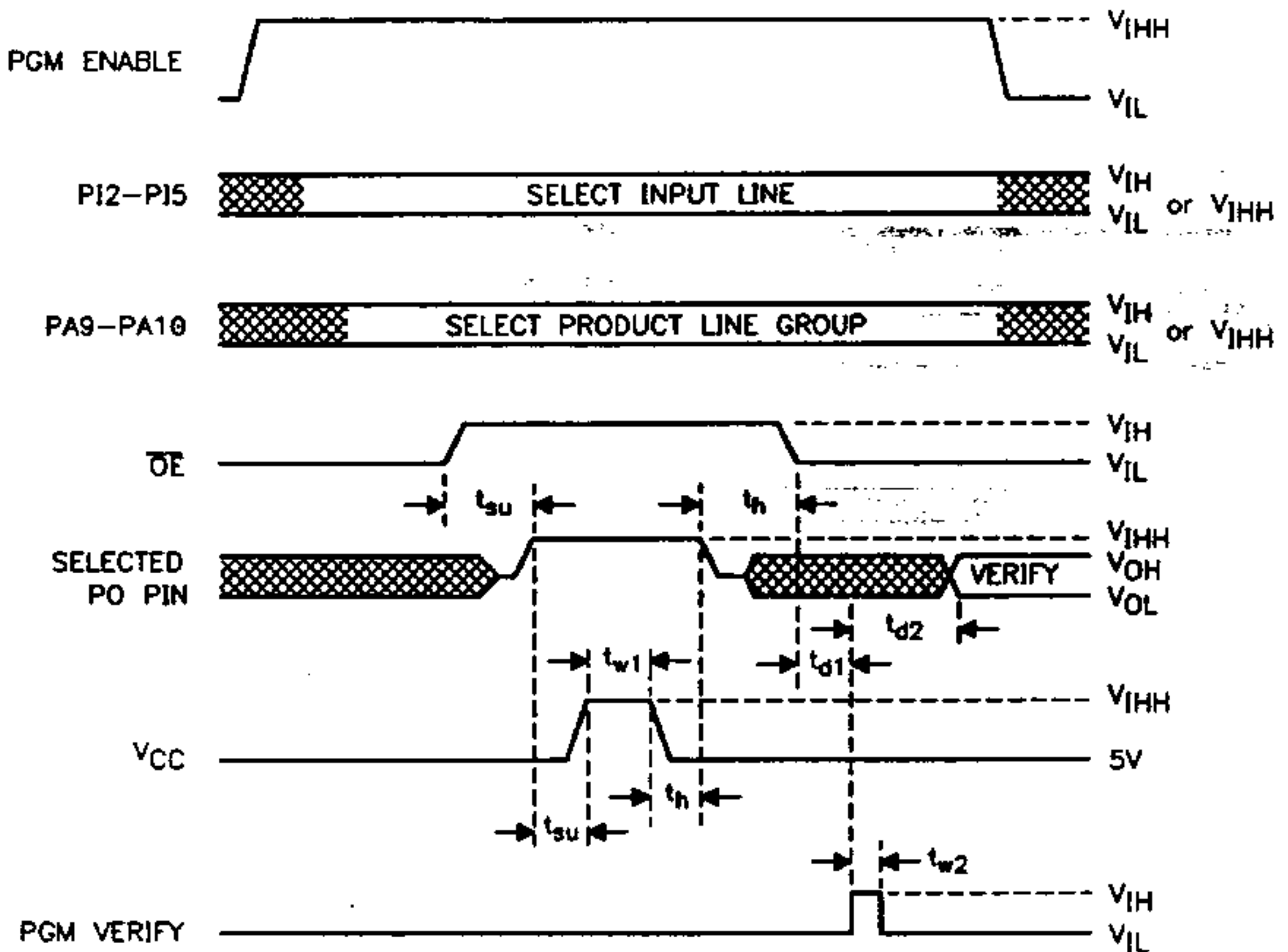
Input Line Number	Input Line Number-Address Pin States			
	PI2	PI3	PI4	PI5
00	L	L	L	L
01	L	L	L	H
02	L	L	L	HH
03	L	L	H	L
04	L	L	H	H
05	L	L	H	HH
06	L	L	HH	L
07	L	L	HH	H
08	L	L	HH	HH
09	L	H	L	L
10	L	H	L	H
11	L	H	L	HH
12	L	H	H	L
13	L	H	H	H
14	L	H	H	HH
15	L	H	HH	L
16	L	H	HH	H
17	L	H	HH	HH
18	L	HH	L	L
19	L	HH	L	H
20	L	HH	L	HH
21	L	HH	H	L
22	L	HH	H	H
23	L	HH	H	HH
24	L	HH	HH	L
25	L	HH	HH	H
26	L	HH	HH	HH
27	H	L	L	L
28	H	L	L	H
29	H	L	L	HH
30	H	L	H	L
31	H	L	H	H
32	H	L	H	HH
33	H	L	HH	L
34	H	L	HH	H
35	H	L	HH	HH
36	H	H	L	L
37	H	H	L	H
38	H	H	L	HH
39	H	H	H	L
SF	X	X	X	X

TABLE 1-3, PRODUCT TERM AND PO SELECTION

PRODUCT TERMS								Address Pin States		
P022	P021	P020	P019	P018	P017	P016	P015	PA9	PA10	
00	08	16	24	32	40	48	56	L	L	
01	09	17	25	33	41	49	57	L	H	
02	10	18	26	34	42	50	58	L	HH	
03	11	19	27	35	43	51	59	H	L	
04	12	20	28	36	44	52	60	H	H	
05	13	21	29	37	45	53	61	H	HH	
06	14	22	30	38	46	54	62	HH	L	
07	15	23	31	39	47	55	63	HH	H	
--	--	--	--	--	SF		--	HH	HH	

SF - When programmed, the array will verify as if it were blank.

FIGURE 1-1, PROGRAMMING WAVEFORMS

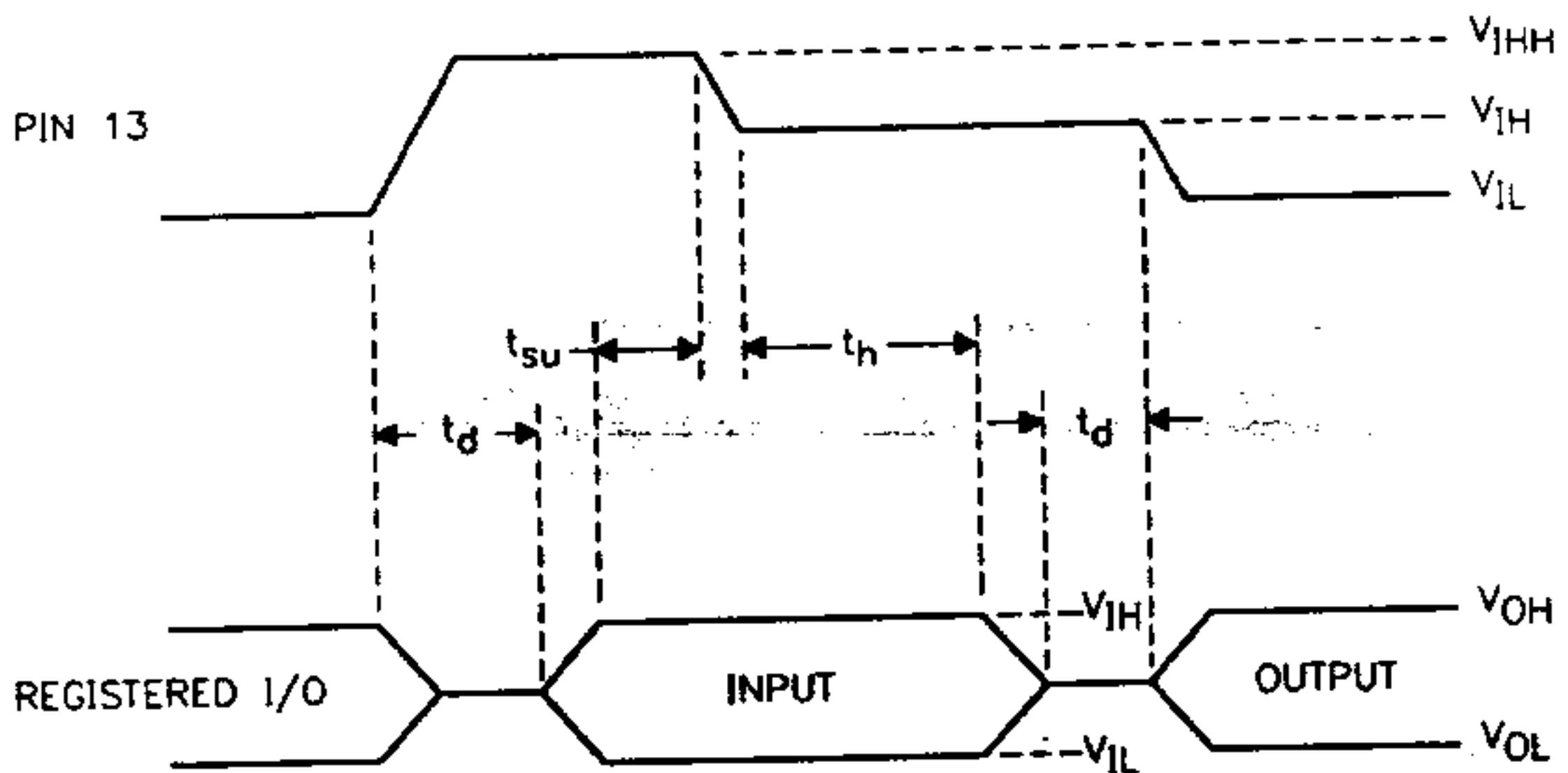


## PRELOAD PROCEDURE FOR REGISTERED OUTPUTS (See Note 1)

The output registers of the TIBPAL20XX-5 can be preloaded to any desired state during device testing. This permits any state to be tested without having to step through the entire state-machine sequence. Each register is preloaded individually by following the steps given below.

- Step 1: With  $V_{CC}$  at 5 volts and pin 1 at  $V_{IL}$ , raise pin 13 to  $V_{IHH}$ .
  - Step 2: Apply either  $V_{IL}$  or  $V_{IH}$  to the output corresponding to the register to be preloaded.
  - Step 3: Lower pin 13 to  $V_{IH}$ .
  - Step 4: Remove output voltage, then lower pin 13 to  $V_{IL}$ .
- Preload can be verified by observing the voltage level at the output pin. Note that the output inverting buffer will have a low output state corresponding to a preloaded high (applied  $V_{IH}$ ) register state.

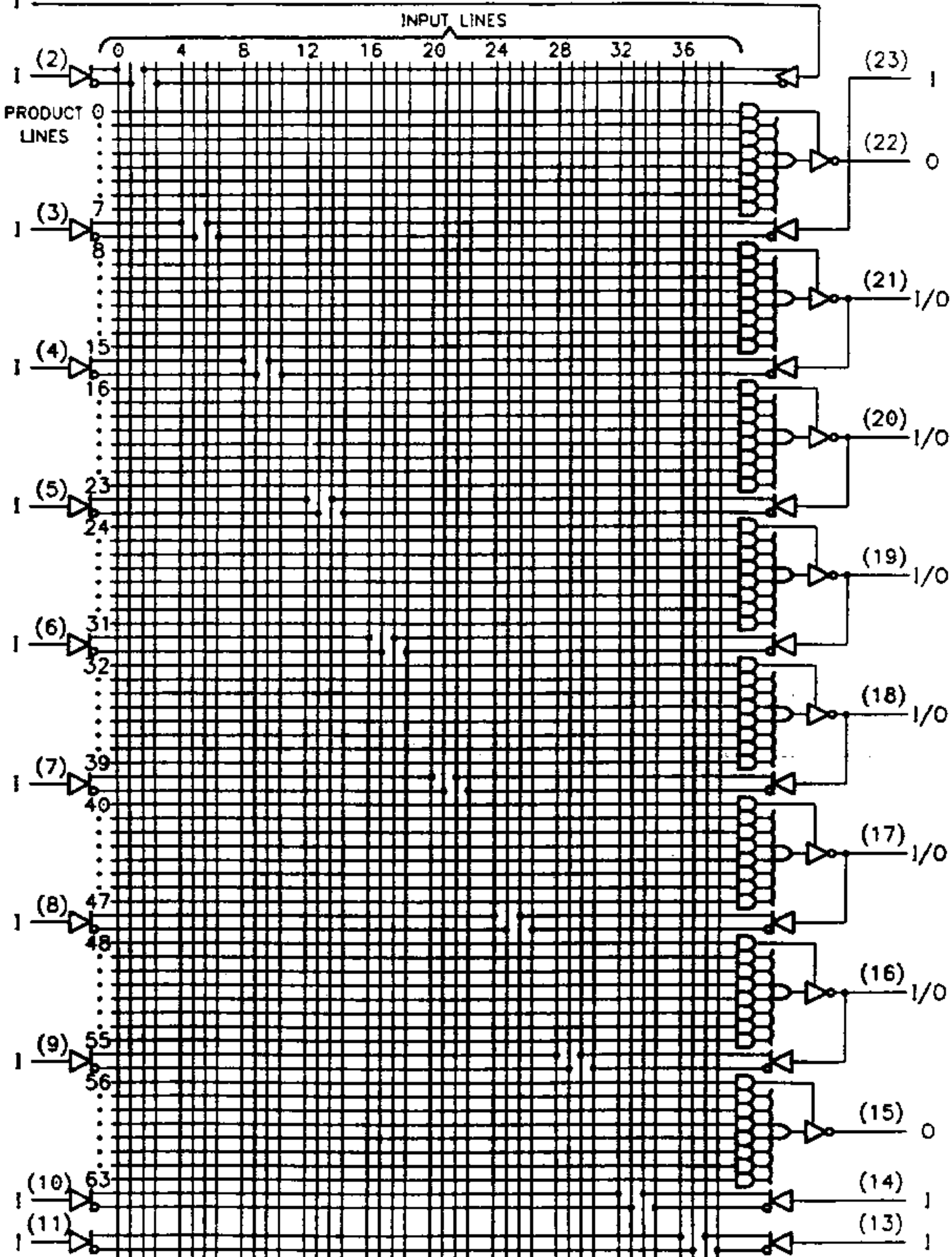
## ASYNCHRONOUS PRELOAD WAVEFORMS (See Notes 1 and 2)



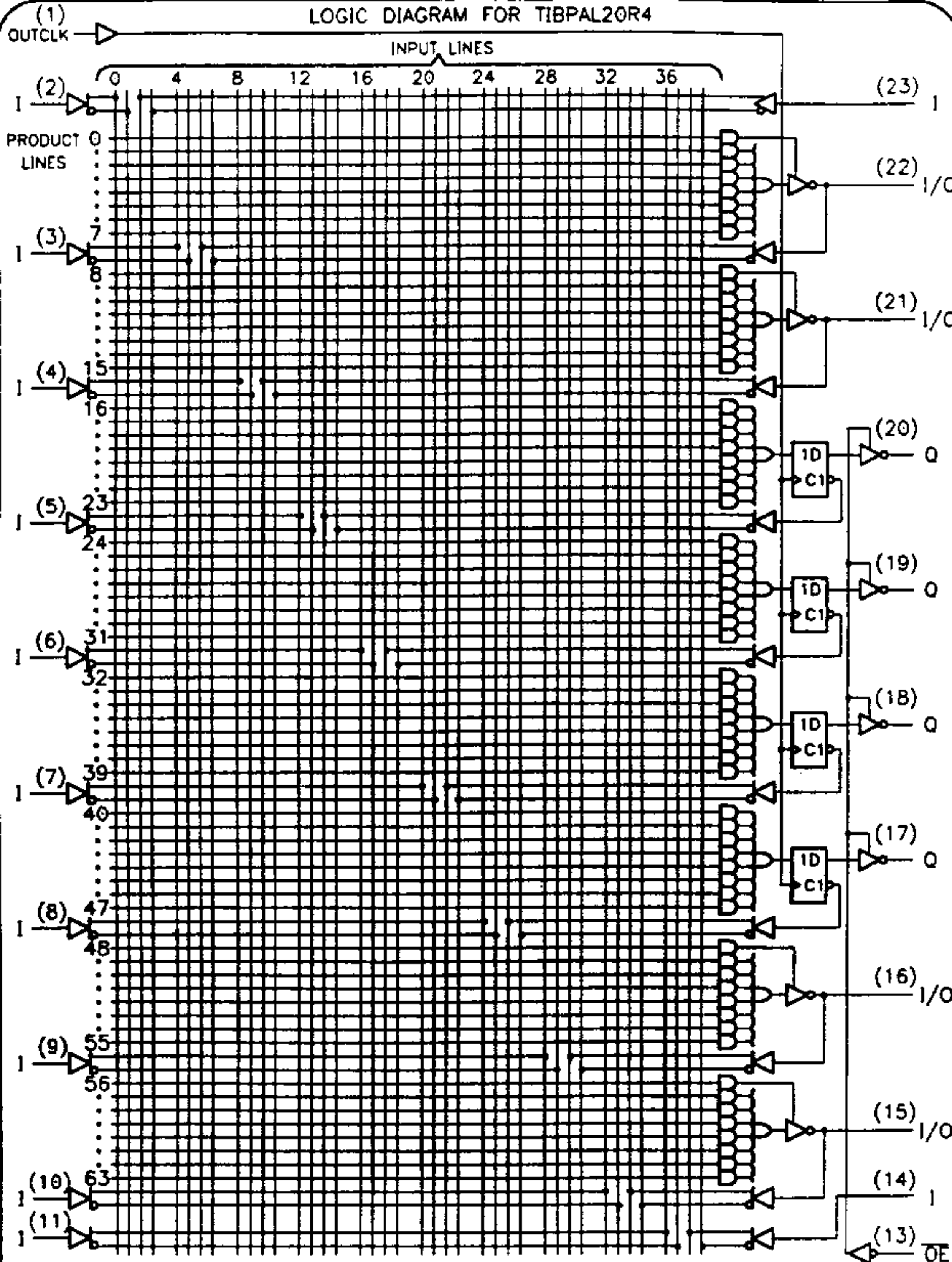
### Notes:

1. Pin number shown is for J or N packages only. For FN or FK packages, pin number must be changed accordingly. (See sheet 2)
2.  $t_d = t_{su} = t_h = 100\text{ns to } 1000\text{ns}$ .  
 $V_{IHH} = 10.25\text{ V to } 10.75\text{ V}$ .

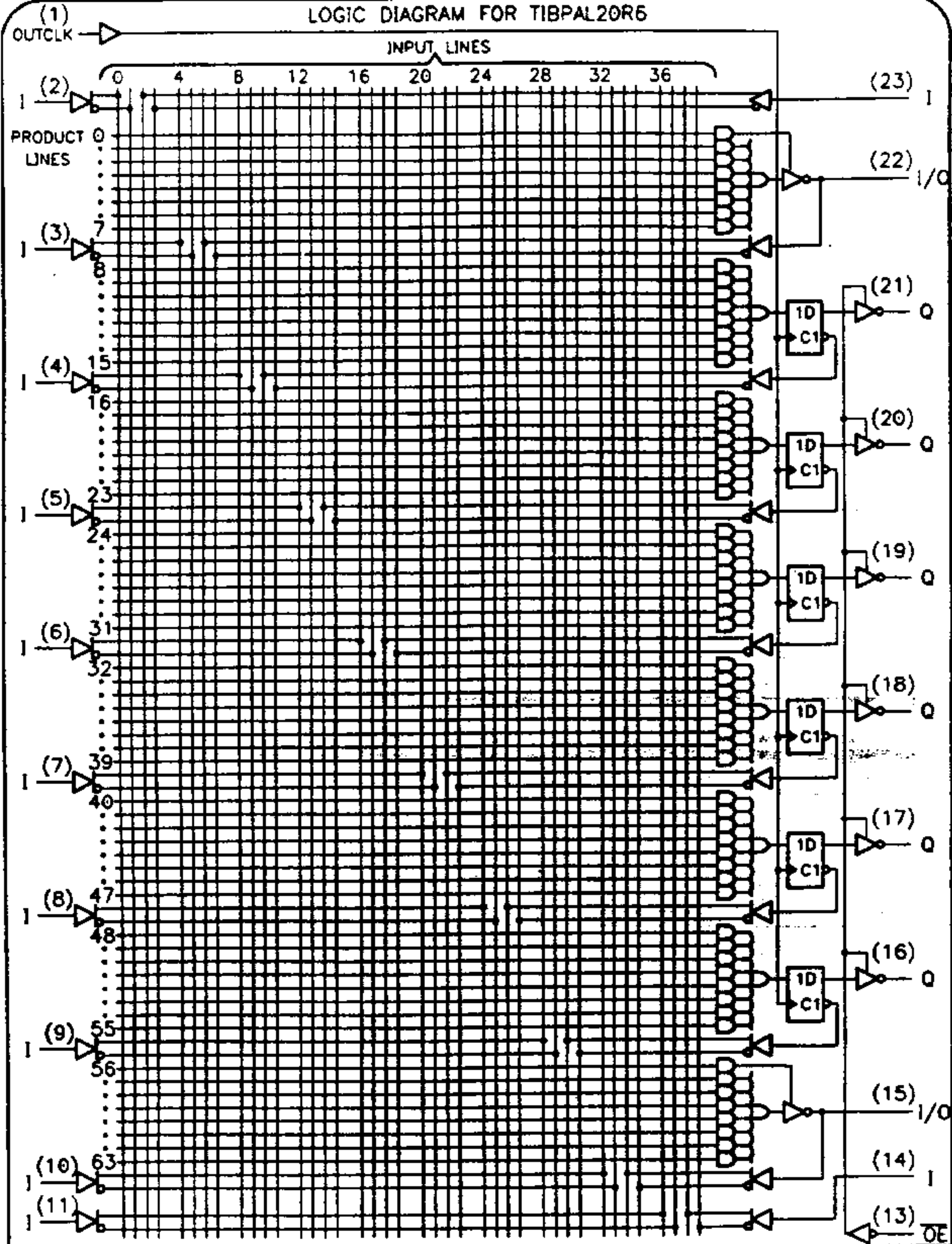
# LOGIC DIAGRAM FOR TIBPAL20L8



# LOGIC DIAGRAM FOR TIBPAL20R4

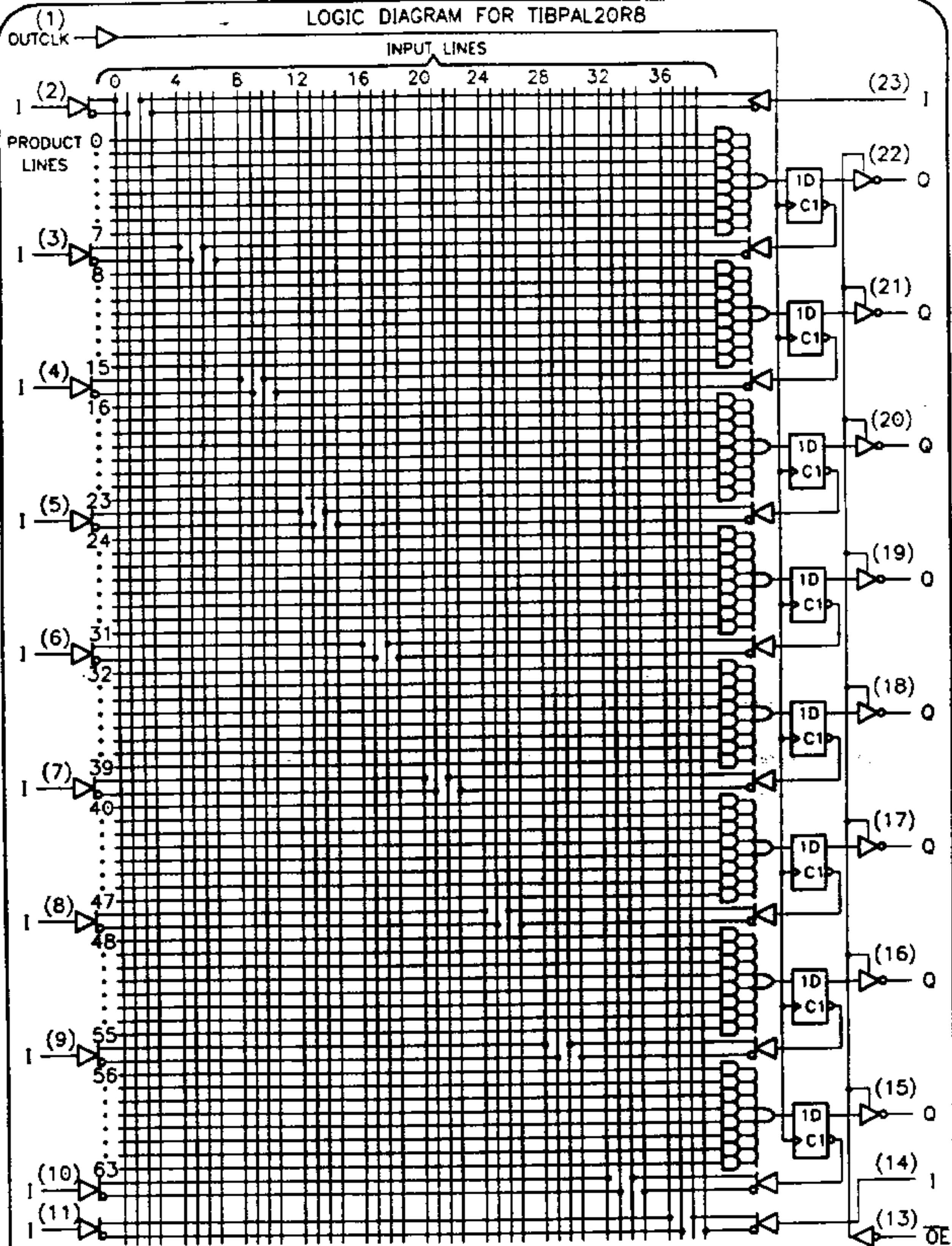


# LOGIC DIAGRAM FOR TIBPAL20R5





# LOGIC DIAGRAM FOR TIBPAL20R8



## REVISION HISTORY

REVISION LTR.	DATE	ENGINEER	DESCRIPTION OF CHANGES
A	06-90	Lippens	Sh 2. Removed MAX Spec. from $t_{su}$ , $t_h$ , and $t_{d1}$ . Sh 3. Removed SF1 & changed SF2 to SF. Sh 4. Table 1-3. Removed SF1 and changed SF2 to SF.
B	06-90	Lippens	Sh 5. Changed from: Pin 11 to Pin 13. Sh 2. DIP - Changed pins 14 and 23 from: GND to: +. PLCC - Changed pins 17 and 27 from: GND to: +. Added note: + = Set to logical "1". Table 1-1: Changed units: $t_{w1}$ from: ns to us $t_{w2}$ from: us to ns $t_{d2}$ from: us to ns Sh 5. Added Notes 1 and 2.